

<b>Notice of References Cited</b>	Application/Control No. 10/712,645		Applicant(s)/Patent Under Reexamination WONG ET AL.	
	Examiner Douglas N. Washburn		Art Unit 2863	Page 1 of 2

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	B	US-6,757,625	06-2004	Adamian et al.	702/57
	C	US-6,744,262	06-2004	Adamian, Vahe' A.	324/638
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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	J	US-			
	K	US-			
	L	US-			
	M	US-			

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